N-Channel Silicon Carbide MOSFET

1200 V, 80 m Ω , TO247–3L

Description

Silicon Carbide (SiC) MOSFET uses a completely new technology that provide superior switching performance and higher reliability compared to Silicon. In addition, the low ON resistance and compact chip size ensure low capacitance and gate charge. Consequently, system benefits include highest efficiency, faster operation frequency, increased power density, reduced EMI, and reduced system size.

Features

- 1200 V @ T_J = 175°C
- Max $R_{DS(on)} = 110 \text{ m}\Omega$ at $V_{GS} = 20 \text{ V}$, $I_D = 20 \text{ A}$
- High Speed Switching with Low Capacitance
- 100% UIL Tested
- Qualified for Automotive According to AEC-Q101
- These Devices are Pb-Free and are RoHS Compliant

Applications

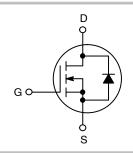
- Automotive Auxiliary Motor Drive
- Automotive On Board Charger
- Automotive DC/DC Converter for EV/HEV



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V _{DSS}	R _{DS(ON)} TYP	I _D MAX
1200 V	80 mΩ	20 A





long leads CASE 340CX

MARKING DIAGRAM



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Data Code (Year & Week)

&K = Lot

NVHL080N120SC1 = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^{\circ}C$, unless otherwise noted)

Symbol	Parameter	Ratings	Unit	
V _{DSmax}	Drain-to-Source Voltage		1200	V
V _{GSmax}	Max. Gate-to-Source Voltage	@ T _C < 175°C	-15 / +25	V
V _{GSop} (DC)	Recommended operation Values of Gate – Source Voltage	@ T _C < 175°C	-5 / +20	V
V _{GSop} (AC)	Recommended operation Values of Gate – Source Voltage (f > 1 Hz)	@ T _C < 175°C	-5 / +20	V
I _D	Continuous Drain Current	V _{GS} = 20 V, T _C = 25°C	44	А
		V _{GS} = 20 V, T _C = 100°C	31	
I _{D(Pulse)}	Pulse Drain Current	Pulse width tp limited by Tj max	136	А
E _{AS}	Single Pulse Avalanche Energy (Note 1)	171	mJ	
P _{tot}	Power Dissipation	T _C = 25°C	348	W
		T _C = 150°C	58	
T _J , T _{STG}	Operating and Storage Junction Temperature	-55 to +175	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. E_{AS} of 171 mJ is based on starting Tj = 25°C, L = 1 mH, I_{AS} = 18.5 A, , V_{DD} = 50 V, R_G = 25 Ω .

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	0.43	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient	40	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
NVHL080N120SC1	NVHL080N120SC1	TO-247 Long Lead	Tube	N/A	N/A	30 Units

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
OFF CHARACT	ERISTICS				ı	1	ı
BV _{DSS}	Drain-to-Source Breakdown Voltage	I _D = 100 μA, V _{GS} = 0 V		1200	_	-	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 5 mA, Referenced t	o 25°C	-	0.3	_	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 1200 V, V _{GS} = 0 V	$T_{C} = 25^{\circ}C$ $T_{C} = 175^{\circ}C$	- -	- -	100 1.0	μA mA
I _{GSS}	Gate-to-Source Leakage Current	V _{GS} = 25 V, V _{DS} = 0 V		-	-	1	μΑ
I _{GSSR}	Gate-to-Source Leakage Current, Reverse	$V_{GS} = -15 \text{ V}, V_{DS} = 0 \text{ V}$		=	-	-1	μΑ
ON CHARACTE	ERISTICS						•
V _{GS(th)}	Gate-to-Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 5 \text{ mA}$		1.8	2.5	4.3	V
R _{DS(on)}	Static Drain-to-Source On Resistance	V _{GS} = 20 V, I _D = 20 A		-	80	110	mΩ
		V _{GS} = 20 V, I _D = 20 A, T	_C = 150°C	-	114	162	
9FS	Forward Transconductance	V _{DS} = 20 V, I _D = 20 A		-	13	-	S
		V _{DS} = 20 V, I _D = 20 A, T	_C = 150°C	-	11	-	
DYNAMIC CHA	RACTERISTICS				ı	1	
C _{iss}	Input Capacitance	V _{DS} = 800 V, V _{GS} = 0 V	, f = 1 MHz	-	1112	1670	pF
C _{oss}	Output Capacitance			-	80	120	pF
C _{rss}	Reverse Transfer Capacitance			-	6.5	10	pF
E _{oss}	C _{oss} Stored Energy	1		_	32	_	μJ
	IARACTERISTICS				I.	I	I
t _{d(on)}	Turn-On Delay Time	V _{CC} = 800 V, I _C = 20 A,		-	6.2	13	ns
t _r	Rise Time	$V_{GS} = -5/20 \text{ V, } R_{G} = 4.7$ Inductive Load, $T_{C} = 25$	'Ω °C	-	5.8	12	ns
t _{d(off)}	Turn-Off Delay Time	, 0		-	28	45	ns
t _f	Fall Time			-	8	16	ns
E _{on}	Turn-on Switching Loss			-	361	_	μJ
E _{off}	Turn-off Switching Loss			_	37	_	μJ
E _{ts}	Total Switching Loss			_	398	_	μJ
Qg	Total Gate Charge	V _{DD} = 600 V, I _D = 20 A		_	56	_	nC
Q _{gs}	Gate-to-Source Charge	$V_{GS} = -5/20 \text{ V}$		_	11	_	nC
Q _{gd}	Gate-to-Drain Charge			-	12	-	nC
R _G	Gate input resistance	f = 1 MHz, D-S short		-	1.7	_	Ω
DIODE CHARA	CTERISTICS				I		l .
V_{SD}	Source-to-Drain Diode Forward	$V_{GS} = -5 V$,	T _C = 25°C	_	4.0	_	V
	Voltage	I _{SD} = 10 A T _C = 150		=	3.4	-	-
E _{rec}	Reverse Recovery Energy	I _{SD} = 20 A,	T _C = 150°C	=	29	-	μJ
t _{rr}	Diode Reverse Recovery Time	Vcc = -5 V.	T _C = 25°C	_	18	_	ns
		$dI_{SD}/dt = 1000 \text{ A/}\mu\text{s}$ $T_C = 150^{\circ}\text{C}$		_	31	_	
Q _{rr}	Diode Reverse Recovery Charge	1	T _C = 25°C	_	80	_	nC
***			T _C = 150°C	_	212	_	
I _{rrm}	Peak Reverse Recovery Current	$T_{C} = 150^{\circ}C$ $T_{C} = 25^{\circ}C$ $T_{C} = 150^{\circ}C$		_	9	_	Α
-11111				_	14		``

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS T_J = 25°C unless otherwise noted

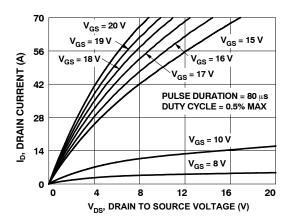


Figure 1. On Region Characteristics

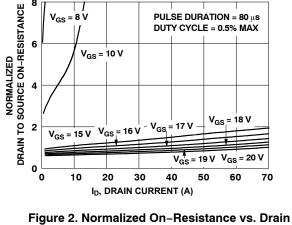


Figure 2. Normalized On–Resistance vs. Drain Current and Gate Voltage

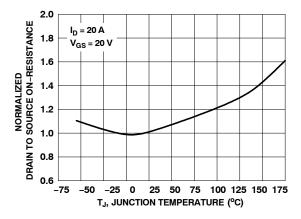


Figure 3. Normalized On Resistance vs. Junction Temperature

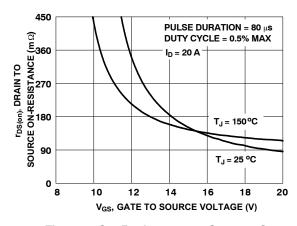


Figure 4. On-Resistance vs. Gate-to-Source Voltage

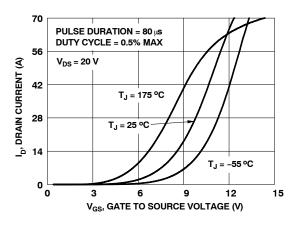


Figure 5. Transfer Characteristics

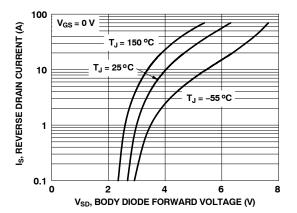


Figure 6. Source-to-Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS T_J = 25°C unless otherwise noted

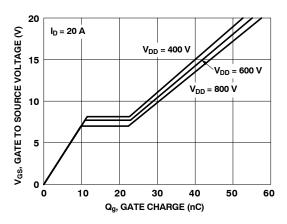


Figure 7. Gate Charge Characteristics

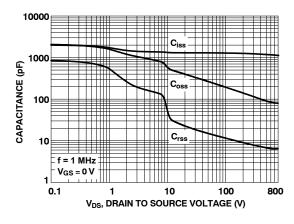


Figure 8. Capacitance vs. Drain-to-Source Voltage

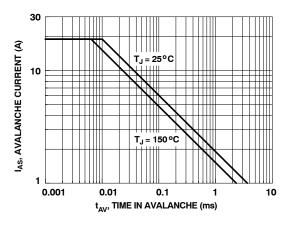


Figure 9. Unclamped Inductive Switching Capability

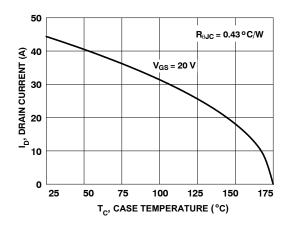


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

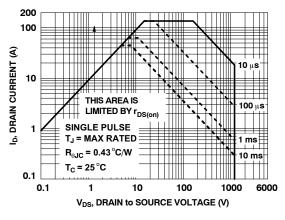


Figure 11. Forward Bias Safe Operating Area

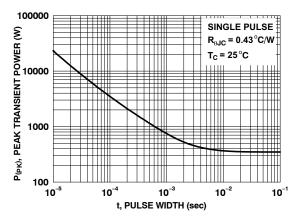


Figure 12. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS $T_J = 25^{\circ}C$ unless otherwise noted

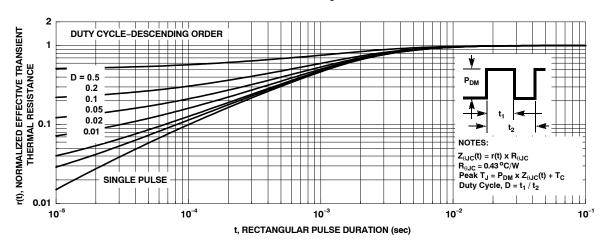
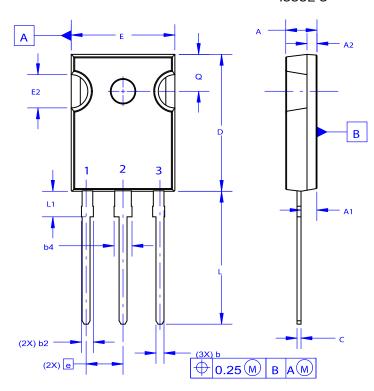


Figure 13. Junction-to-Case Transient Thermal Response Curve

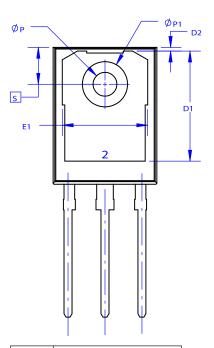
PACKAGE DIMENSIONS

TO-247-3LD CASE 340CX ISSUE O



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.



DIM	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	4.58	4.70	4.82			
A 1	2.20	2.40	2.60			
A2	1.40	1.50	1.60			
D	20.32	20.57	20.82			
Е	15.37	15.62	15.87			
E2	4.96	5.08	5.20			
е	?	5.56	?			
L	19.75	20.00	20.25			
L1	3.69	3.81	3.93			
ØР	3.51	3.58	3.65			
Q	5.34	5.46	5.58			
S	5.34	5.46	5.58			
b	1.17	1.26	1.35			
b2	1.53	1.65	1.77			
b4	2.42	2.54	2.66			
С	0.51	0.61	0.71			
D1	13.08	2	~			
D2	0.51	0.93	1.35			
E1	12.81	1	?			
ØP1	6.60	6.80	7.00			

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